

FACULTY OF SCIENCE AND MATHEMATICS UNIVERSITI PENDIDIKAN SULTAN IDRIS

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No Rujukan JPPS

20__- FSM/J__/_
(BIL___/__)

UPSI/ESM/JPPS(Pin 04)

APPLICATION FOR SAMPLE ANALYSIS HIGH RESOLUTION FIELD EMISSION SCANNING ELECTRON MICROSCOPE (FESEM)

PART	A: APPLICANT INFORMAT	TION							
Applicant Name :		:	Phone No : Department :						
Vot / Grant No. : Cu						rent Balance :			
			e (coursework @ Thesis)/GRA/RA External						
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PART B: SAMPLE INFORMATION									
Type o	f Analysis : SEM		STEM		EDX (o	ption)			
Bil Name of Sample			(Con	Nature of Conductivity (Conductive or non- conductive) Type of Sa (Solid or Li				ample Number	
1								1 Only	
					•				
PART C: DECLARATION									
STUDENT / STAFF DECLARATION SUPERVISOR / LECTURER DECLARATION									
respo Name Date			Isification	Name :	*	ost set by the F Mathematics. (If Applicable Only) gnature & Stan	·)	elence and	
PART D: APPROVAL BY SCIENTIFIC INSTRUMENT COORDINATOR									
Name Date Operat	OFFI or Name : red Date : eted Date :	CE USE	DINATOR :	1. Pleas 2. For S' copper g 3. Follow	TE e make sure TEM analysis ırid for each s	RMS OF APPL that you clean s, student / staft sample.	the "sampl f must pro	e stub" after use. vide their own y the Department	
TOTAL AMOUNT (RM) :				PAYMENT RATE					
	•					SEM		EDX	
					JPSI	RM40.0	UU	RM30.00	

External

Urgent Analysis

(UPSI & External)

RM200.00

RM250.00

RM70.00

RM100.00